

Notice of References Cited	Application/Control No. 10/650,365	Applicant(s)/Patent Under Reexamination WEI ET AL.	
	Examiner Jegatheesan Seharaseyon, Ph.D	Art Unit 1647	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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FOREIGN PATENT DOCUMENTS

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	N	EP422697A1	04-1991		Alton et al.	
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NON-PATENT DOCUMENTS

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